# **Dual Variable-Reluctance Sensor Interface IC**

The CS1124 is a monolithic integrated circuit designed primarily to condition signals used to monitor rotating parts.

The CS1124 is a dual channel device. Each channel interfaces to a Variable Reluctance Sensor, and monitors the signal produced when a metal object is moved past that sensor. An output is generated that is a comparison of the input voltage and the voltage produced at the IN  $_{\mbox{\sc Adj}}$  lead. The resulting square—wave is available at the OUT pin.

When the DIAG pin is high, the reference voltage at  $IN_{Adj}$  is increased. This then requires a larger signal at the input to trip the comparator, and provides for a procedure to test for an open sensor.

#### **Features**

- Dual Channel Capability
- Built-In Test Mode
- On-Chip Input Voltage Clamping
- Works from 5.0 V Supply
- Accurate Built-In Hysteresis

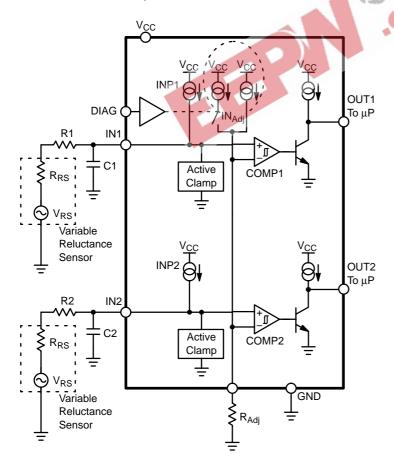


Figure 1. Block Diagram

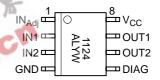


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## PIN CONNECTIONS AND MARKING DIAGRAM



A = Assembly Location

WL, L = Wafer Lot YY, Y = Year WW, W = Work Week

#### ORDERING INFORMATION

Device	Package Shipping	
CS1124YD8	SO-8	95 Units/Rail
CS1124YDR8	SO-8	2500 Tape & Reel

#### **MAXIMUM RATINGS\***

Rating	Value	Unit	
Storage Temperature Range		-65 to 150	°C
Ambient Operating Temperature		-40 to 125	°C
Supply Voltage Range (continuous)		-0.3 to 7.0	V
Input Voltage Range (at any input, R1 = R2 = 22 k)		-250 to 250	V
Maximum Junction Temperature		150	°C
ESD Susceptibility (Human Body Model)		2.0	kV
Lead Temperature Soldering:	Reflow: (SMD styles only) (Note 1)	230 peak	°C

<sup>1. 60</sup> second maximum above 183°C.

## 

Characteristic	Test Conditions	Min	Тур	Max	Unit
V <sub>CC</sub> SUPPLY					
Operating Current Supply	V <sub>CC</sub> = 5.0 V	0	-	5.0	mA
Sensor Inputs		水水石			
Input Threshold – Positive	V <sub>DIAG</sub> = Low V <sub>DIAG</sub> = High	135 1 <b>35</b>	160 160	185 185	mV mV
Input Threshold – Negative	V <sub>DIAG</sub> = Low V <sub>DIAG</sub> = High	-185 135	-160 160	-135 185	mV mV
Input Bias Current (INP1, INP2)	V <sub>IN</sub> = 0.336 V	-16	-11	-6.0	μΑ
Input Bias Current (DIAG)	V <sub>DIAG</sub> = 0 V	_	-	1.0	μΑ
Input Bias Current Factor (K <sub>I</sub> ) (IN <sub>Adj</sub> = INP × K <sub>I</sub> )	$V_{IN}$ = 0.336 V, $V_{DIAG}$ = Low $V_{IN}$ = 0.336 V, $V_{DIAG}$ = High	_ 152	100 155	_ 157	%INP %INP
Bias Current Matching	INP1 or INP2 to IN <sub>Adj</sub> , V <sub>IN</sub> = 0.336 V	-1.0	0	1.0	μΑ
Input Clamp – Negative	$I_{IN} = -50 \mu A$ $I_{IN} = -12 \text{ mA}$	-0.5 -0.5	-0.25 -0.30	0 0	V V
Input Clamp – Positive	I <sub>IN</sub> = +12 mA	5.0	7.0	9.0	V
Output Low Voltage	I <sub>OUT</sub> = 1.6 mA	_	0.2	0.4	V
Output High Voltage	I <sub>OUT</sub> = -1.6 mA	V <sub>CC</sub> - 0.5	V <sub>CC</sub> - 0.2	-	V
Mode Change Time Delay	-	0	_	20	μs
Input to Output Delay	I <sub>OUT</sub> = 1.0 mA	_	1.0	20	μs
Output Rise Time	C <sub>LOAD</sub> = 30 pF	_	0.5	2.0	μs
Output Fall Time	C <sub>LOAD</sub> = 30 pF	_	0.05	2.0	μs
Open–Sensor Positive Threshold	V <sub>DIAG</sub> = High, R <sub>IN(Adj)</sub> = 40 k. Note 2	29.4	54	86.9	kΩ
Logic Inputs					
DIAG Input Low Threshold		_	-	0.2 × V <sub>CC</sub>	V
DIAG Input High Threshold	-	$0.7 \times V_{CC}$	-	-	V
DIAG Input Resistance	$\begin{aligned} &V_{IN} = 0.3 \times V_{CC} \;,  V_{CC} = 5.0 \; V \\ &V_{IN} = V_{CC},  V_{CC} = 5.0 \; V \end{aligned}$	8.0 8.0	22 22	70 70	kΩ kΩ

<sup>2.</sup> This parameter is guaranteed by design, but not parametrically tested in production.

<sup>\*</sup>The maximum package power dissipation must be observed.

#### **PACKAGE PIN DESCRIPTION\***

PACKAGE PIN #		
SO-8	PIN SYMBOL	FUNCTION
1	$IN_{Adj}$	External resistor to ground that sets the trip levels of both channels. Functions for both diagnostic and normal mode.
2	IN1	Input to channel 1.
3	IN2	Input to channel 2.
4	GND	Ground.
5	DIAG	Diagnostic mode switch. Normal mode is low.
6	OUT2	Output of channel 2.
7	OUT1	Output of channel 1.
8	V <sub>CC</sub>	Positive 5.0 volt supply input.

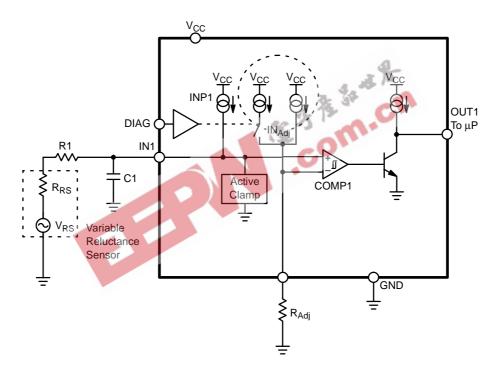


Figure 2. Application Diagram

#### THEORY OF OPERATION

#### **NORMAL OPERATION**

Figure 2 shows one channel of the CS1124 along with the necessary external components. Both channels share the  $IN_{Adj}$  pin as the negative input to a comparator. A brief description of the components is as follows:

 $V_{RS}$  – Ideal sinusoidal, ground referenced, sensor output – amplitude usually increases with frequency, depending on loading.

 $R_{RS}$  – Source impedance of sensor.

 $R1/R_{Adj}$  – External resistors for current limiting and biasing.

 $INP1/IN_{Adj}$  – Internal current sources that determine trip points via  $R1/R_{Adj}.$ 

**COMP1** – Internal comparator with built–in hysteresis set at 160 mV.

OUT1 — Output 0 V — 5.0 V square wave with the same frequency as  $V_{RS}$ .

By inspection, the voltage at the (+) and (–) terminals of COMP1 with  $V_{RS} = 0V$  are:

$$V^{+} = INP1(R1 + RRS)$$
 (1)

$$V^- = IN_{Adj} \times R_{Adj}$$
 (2)

As  $V_{RS}$  begins to rise and fall, it will be superimposed on the DC biased voltage at  $V^+$ .

$$V^{+} = INP1(R1 + RRS) + VRS$$
 (3)

To get comparator COMP1 to trip, the following condition is needed when crossing in the positive direction,

$$V^{+} > V^{-} + V_{HYS} \tag{4}$$

 $(V_{HYS})$  is the built-in hysteresis set to 160 mV), or when crossing in the negative direction,

$$V^{+} < V^{-} - V_{HYS} \tag{5}$$

Combining equations 2, 3, and 4, we get:

$$INP1(R1 + RRS) + VRS > INAdj \times RAdj + VHYS$$
 (6)

therefore.

$$V_{RS(+TRP)} < IN_{Adj} \times R_{Adj} - INP1(R1 + R_{RS}) + V_{HYS}$$
(7)

It should be evident that tripping on the negative side is:

$$V_{RS(-TRP)} < IN_{Adj} \times R_{Adj} - INP1(R1 + R_{RS}) - V_{HYS}$$

In normal mode,

$$INP1 = IN_{Adj}$$
 (9)

We can now re-write equation (7) as:

$$V_{RS(+TR)} > INP1(R_{Adj} - R1 - R_{RS}) + V_{HYS}$$
 (10)

By making

$$RAdi = R1 + RRS \tag{11}$$

you can detect signals with as little amplitude as  $V_{HYS}$ . A design example is given in the applications section.

#### **OPEN SENSOR PROTECTION**

The CS1124 has a DIAG pin that when pulled high (5.0 V), will increase the IN<sub>Adi</sub> current source by roughly 50%.

Equation (7) shows that a larger  $V_{RS(+TRP)}$  voltage will be needed to trip comparator COMP1. However, if no  $V_{RS}$  signal is present, then we can use equations 1, 2, and 4 (equation 5 does not apply in this mode) to get:

$$INP1(R1 + R_{RS}) > INP1 \times K_I \times R_{Adj} + V_{HYS}$$
 (12)

Since  $R_{RS}$  is the only unknown variable we can solve for  $R_{RS}$ ,

$$RRS = \frac{INP1 \times K_I \times RAdj + V_{HYS}}{INP1} - R1$$
 (13)

Equation (13) shows that if the output switches states when entering the diag mode with  $V_{RS}=0$ , the sensor impedance must be greater than the above calculated value. This can be very useful in diagnosing intermittent sensor.

#### INPUT PROTECTION

As shown in Figure 2, an active clamp is provided on each input to limit the voltage on the input pin and prevent substrate current injection. The clamp is specified to handle  $\pm 12$  mA. This puts an upper limit on the amplitude of the sensor output. For example, if R1 = 20 k, then

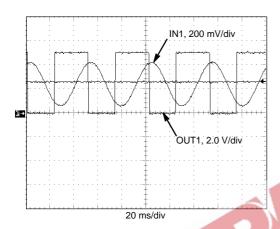
$$VRS(MAX) = 20 k \times 12 mA = 240 V$$

Therefore, the  $V_{RS(pk-pk)}$  voltage can be as high as 480 V. The CS1124 will *typically* run at a frequency up to 1.8 MHz if the input signal does not activate the positive or negative input clamps. Frequency performance will be lower when the positive or negative clamps are active. *Typical* performance will be up to a frequency of 680 kHz with the clamps active.

#### **CIRCUIT DESCRIPTION**

Figure 3 shows the part operating near the minimum input thresholds. As the sin wave input threshold is increased, the low side clamps become active (Figure 4). Increasing the amplitude further (Figure 5), the high–side clamp becomes active. These internal clamps allow for voltages up to -250~V and 250~V on the sensor side of the setup (with R1 = R2 = 22~k) (reference the diagram page 1).

Figure 6 shows the effect using the diagnostic (DIAG) function has on the circuit. The input threshold (negative) is switched from a threshold of -160~mV to +160~mV when DIAG goes from a low to a high. There is no hysteresis when DIAG is high.



**Figure 3. Minimum Threshold Operation** 

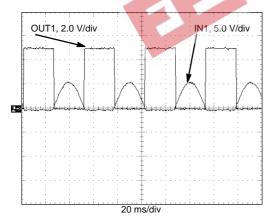


Figure 4. Low-Side Clamp

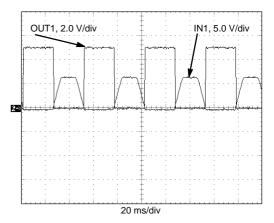


Figure 5. Low- and High-Side Clamps

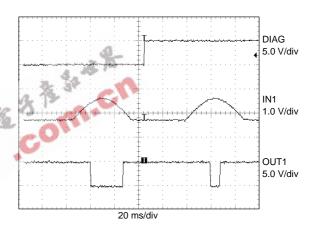


Figure 6. Diagnostic Operation

#### **APPLICATION INFORMATION**

Referring to Figure 2, the following will be a design example given these system requirements:

RRS = 
$$1.5 \text{ k}\Omega$$
 (>  $12 \text{ k}\Omega$  is considered open)

$$V_{RS(MAX)} = 120 V_{pk}$$

$$V_{RS(MIN)} = 250 \text{ mV}_{DK}$$

$$FVRS = 10 \text{ kHz} @ VRS(MIN) = 40 Vpk-pk$$

## 1. Determine tradeoff between R1 value and power rating. (use 1/2 watt package)

$$P_D = \frac{\left(\frac{120}{\sqrt{2}}\right)^2}{R1} < 1/2 W$$

Set R1 = 15 k. (The clamp current will then be 120/15 k = 8.0 mA, which is less than the 12 mA limit.)

#### 2. Determine R<sub>Adi</sub>

Set  $R_{Adj}$  as close to  $R1 + R_{RS}$  as possible. Therefore,  $R_{Adj} = 17$  k.

#### 3. Determine V<sub>RS(+TRP)</sub> using equation (7).

$$VRS(+TRP) = 11\mu A \times 17k - 11\mu A(15k + 1.5k) + 160 \text{ mV}$$

#### 4. Calculate worst case V<sub>RS(+TRP)</sub>

Examination of equation (7) and the spec reveals the worst case trip voltage will occur when:

 $V_{HYS} = 180 \text{ mV}$ 

 $IN_{Adj} = 16 \mu A$ 

 $INP1 = 15 \mu A$ 

R1 = 14.25 k (5% low)

 $R_{Adi} = 17.85 \text{ k } (5\% \text{ High})$ 

$$\begin{split} VRS(+)MAX &= 16 \ \mu A (17.85 \ k) \\ &- 15 \mu A (14.25 \ k + 1.5 \ k) \, + \, 180 \ mV \\ &= 229 \ mV \end{split}$$

which is still less than the 250 mV minimum amplitude of the input.

#### 5. Calculate C1 for low pass filtering

Since the sensor guarantees 40  $V_{pk-pk}$  @ 10 kHz, a low pass filter using R1 and C1 can be used to eliminate high frequency noise without affecting system performance.

Gain Reduction = 
$$\frac{0.29 \text{ V}}{20 \text{ V}}$$
 = 0.0145 = -36.7 dB

Therefore, a cut-off frequency,  $f_{\text{C}}$ , of 145 Hz could be used.

$$C1 \le \frac{1}{2\pi f_C R1} \le 0.07 \,\mu\text{F}$$

Set C1 =  $0.047 \,\mu\text{F}$ .

# 6. Calculate the minimum $R_{RS}$ that will be indicated as an open circuit. (DIAG = 5.0 V)

Rearranging equation (7) gives

$$R_{RS} = \frac{\begin{bmatrix} V_{HYS} + [INP1 \times K_{I} \times R_{Adj}] \\ - V_{RS}(+TRP) \end{bmatrix}}{INP1} - R1$$

But,  $V_{RS} = 0$  during this test, so it drops out.

Using the following as worst case Low and High:

Worst Case Low (R <sub>RS</sub> )		Worst Case High (R <sub>RS</sub> )	
IN <sub>Adj</sub>	$23.6 \mu\text{A} = 15 \mu\text{A} \times 1.57$	$10.7 \mu\text{A} = 7.0 \mu\text{A} \times 1.53$	
R <sub>Adj</sub>	16.15 k	17.85 k	
V <sub>HYS</sub>	135 mV	185 mV	
INP1	16 μΑ	6.0 μΑ	
R1	15.75 k	14.25 k	
Kı	1.57	1.53	

$$RRS = \frac{135 \text{ mV} + 23.6 \,\mu\text{A} \times 16.15 \,k}{16 \,\mu\text{A}} - 15.75 \,k$$
$$= 16.5 \,k$$

Therefore,

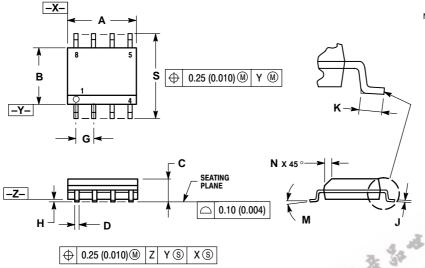
RRS(MIN) = 16.5 k (meets 12 k system spec)

and,

RRS(MAX) = 
$$\frac{185 \text{ mV} + 10.7 \mu\text{A} \times 17.85 \text{ k}}{6.0 \mu\text{A}} - 14.25 \text{ k}$$
$$= 48.4 \text{ k}$$

#### **PACKAGE DIMENSIONS**

#### SO-8 **D SUFFIX** CASE 751-07 ISSUE V



#### NOTES:

- NOTES:

  1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

  2. CONTROLLING DIMENSION: MILLIMETER.

  3. DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.

  4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- 4. MAXIMUM MOLD PHOTROSION 9.19 (9.000). . . . . SIDE.
  SIDE

#### **PACKAGE THERMAL DATA**

Parameter		SO-8	Unit
$R_{\Theta JC}$	Typical	45	°C/W
$R_{\Theta JA}$	Typical	165	°C/W



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